

IRFZ44EL-VB Datasheet Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	60				
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.015				
Q _g (Max.) (nC)	110				
Q _{gs} (nC)	29				
Q _{gd} (nC)	36				
Configuration	Single				

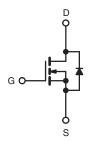
FEATURES

- · Advanced process technology
- 175 °C operating temperature
- · Fast switching









N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	60	W	
Gate-Source Voltage			V_{GS}	± 20	- V	
Continuous Drain Current f	\/ at 10 \/	t 10 V $\frac{T_C = 25 \text{ °C}}{T_C = 100 \text{ °C}}$	I _D	60	А	
Continuous Drain Current	V _{GS} at 10 V			50		
Pulsed Drain Current a, e			I _{DM}	290		
Linear Derating Factor				1.3	W/°C	
Single Pulse Avalanche Energy b, e			E _{AS}	100	mJ	
Maximum Bayyar Dissination	T _C = 25 °C		ם	190	10/	
Maximum Power Dissipation	T _A = 25 °C		P _D	3.7	W	
Peak Diode Recovery dV/dt c, e			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	T _J , T _{sta} -55 to +175		
oldering Recommendations (Peak temperature) d for 10 s		_	300	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=25$ V, Starting $T_J=25$ °C, L=22 μH , $R_g=25$ Ω , $I_{AS}=72$ A (see fig. 12). c. $I_{SD}\leq 72$ A, $dI/dt\leq 200$ A/ μs , $V_{DD}\leq V_{DS}$, $T_J\leq 175$ °C. d. 1.6 mm from case. e. Uses IRFZ48, SiHFZ48 data and test conditions.

- f. Calculated continuous current based on maximum allowable junction temperature.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB mount) ^a	R _{thJA}	-	40	°C/W	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.8		

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		_			•		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	$V_{GS} = 0$, $I_D = 250 \mu\text{A}$		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA ^c	-	0.060	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	1.5	-	3.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS}	= 60 V, V _{GS} = 0 V	-	-	25	μА
Zero date voltage Brain ourrent	טיטי	$V_{DS} = 48 \text{ V}$	$V_{GS} = 0 V, T_{J} = 150 °C$	-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}$	I _D = 15 A ^b	-	0.015	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	= 25 V, I _D = 15 A ^b	27	-	ı	S
Dynamic							
Input Capacitance	C_{iss}	V _{GS} = 0 V,		-	3500	-	pF
Output Capacitance	C_{oss}		V _{DS} = 25 V, f = 1.0 MHz, see fig. 5 °		1300	ı	
Reverse Transfer Capacitance	C_{rss}	f = 1.			190	ı	
Total Gate Charge	Q_g			-	-	110	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$	$V_{GS} = 10 \text{ V}$ $I_D = 12 \text{ A}, V_{DS} = 48 \text{ V},$ see fig. 6 and 13 b, c		-	29	nC
Gate-Drain Charge	$Q_{\sf gd}$				-	36	
Turn-On Delay Time	t _{d(on)}	V _{DD} = 30 V, I _D = 12 A,		-	8.1	-	ns
Rise Time	t _r			-	250	-	
Turn-Off Delay Time	$t_{d(off)}$	$R_g = 9.1 \Omega, R$	$R_g = 9.1 \ \Omega$, $R_D = 0.34 \ \Omega$, see fig. 10 b, c		210	ı	
Fall Time	t _f				250	-	
Internal Source Inductance	L _S	Between lead, and center of die contact		-	7.5	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the			-	50°	A
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	90	
Body Diode Voltage	V _{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 72 \text{A}, V_{GS} = 0 \text{V}^{ \text{b}}$		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 72 A, dl/dt = 100 A/µs b, c		-	120	180	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	500	800	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)					L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width $\leq 300~\mu s$; duty cycle $\leq 2~\%.$ c. Uses VBL1615/IRFZ44EL-VB data and test conditions.

- d. Calculated continuous current based on maximum allowable junction temperature.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

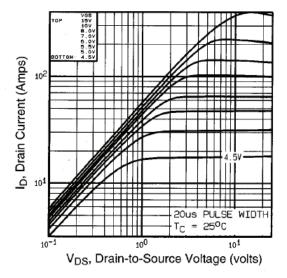


Fig. 1 - Typical Output Characteristics

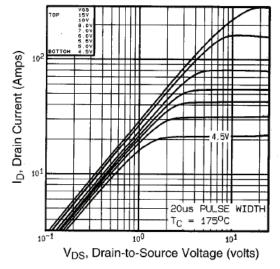


Fig. 2 - Typical Output Characteristics

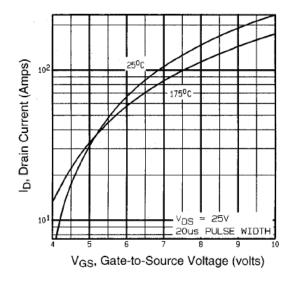


Fig. 3 - Typical Transfer Characteristics

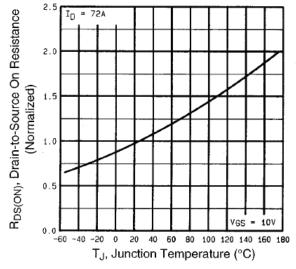


Fig. 4 - Normalized On-Resistance vs. Temperature



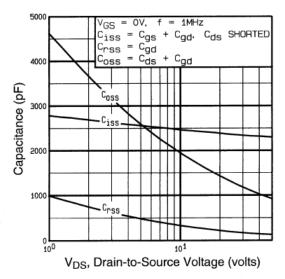


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

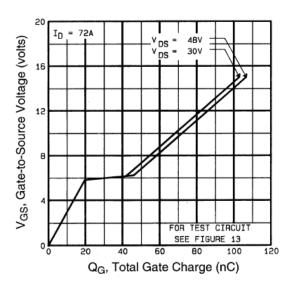


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

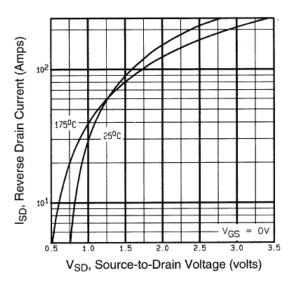


Fig. 7 - Typical Source-Drain Diode Forward Voltage

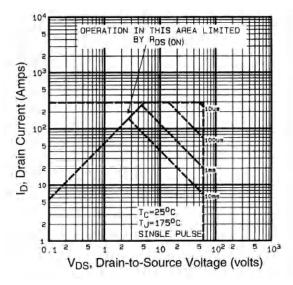


Fig. 8 - Maximum Safe Operating Area



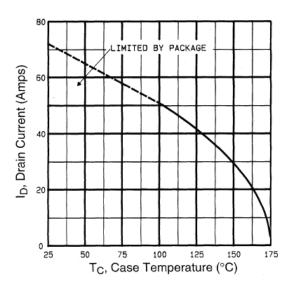


Fig. 9 - Maximum Drain Current vs. Case Temperature

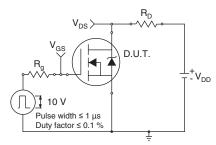


Fig. 10a - Switching Time Test Circuit

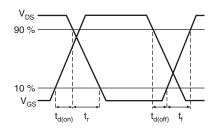
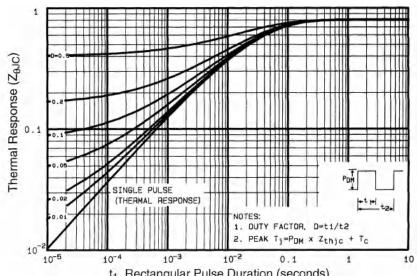


Fig. 10b - Switching Time Waveform



 $t_1,\,Rectangular\,Pulse\,Duration\,(seconds)\\ \mbox{Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case}$

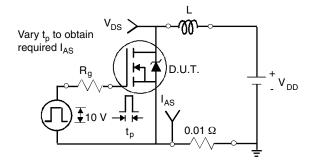


Fig. 12a - Unclamped Inductive Test Circuit

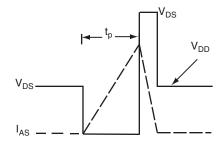


Fig. 12b - Unclamped Inductive Waveforms



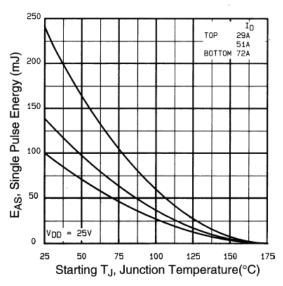


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

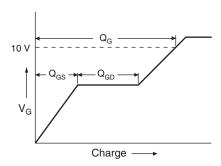


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

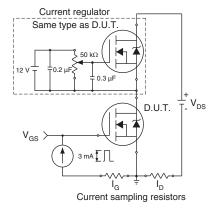
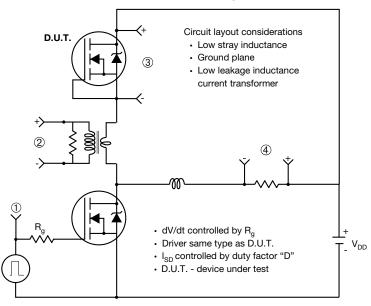


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



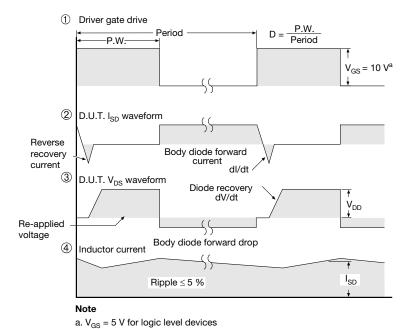
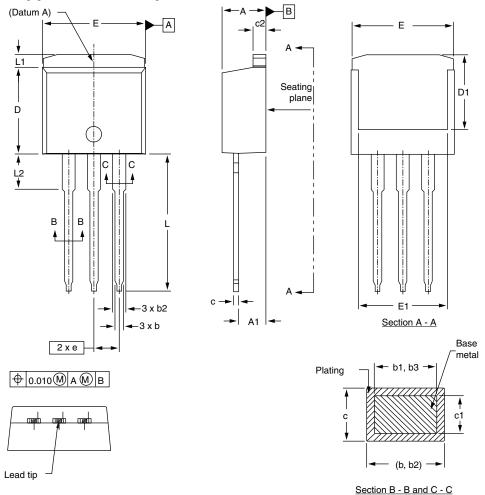


Fig. 14 - For N-Channel



I²PAK (TO-262) (HIGH VOLTAGE)



	MILLIN	METERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	2.03	3.02	0.080	0.119
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D	8.38	9.65	0.330	0.380
D1	6.86	-	0.270	-
E	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
L	13.46	14.10	0.530	0.555
L1	-	1.65	-	0.065
L2	3.56	3.71	0.140	0.146

Scale: None

ECN: S-82442-Rev. A, 27-Oct-08

DWG: 5977

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm per side. These dimensions are measured at the outmost extremes of the plastic body.
- 3. Thermal pad contour optional within dimension E, L1, D1, and E1.
- 4. Dimension b1 and c1 apply to base metal only.



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